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## Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

#### Details

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Product Status	Not For New Designs
Core Processor	TriCore™
Core Size	32-Bit Single-Core
Speed	133MHz
Connectivity	ASC, CANbus, MLI, MSC, SSC
Peripherals	DMA, POR, WDT
Number of I/O	88
Program Memory Size	2MB (2M x 8)
Program Memory Type	FLASH
EEPROM Size	·
RAM Size	128K x 8
Voltage - Supply (Vcc/Vdd)	1.42V ~ 1.58V
Data Converters	A/D 4x10b, 32x12b
Oscillator Type	External
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	176-LQFP
Supplier Device Package	PG-LQFP-176-5
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/tc1767256f133hradkfqma1

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



# 2 Introduction

This Data Sheet describes the Infineon TC1767, a 32-bit microcontroller DSP, based on the Infineon TriCore Architecture.

## 2.1 About this Document

This document is designed to be read primarily by design engineers and software engineers who need a detailed description of the interactions of the TC1767 functional units, registers, instructions, and exceptions.

This TC1767 Data Sheet describes the features of the TC1767 with respect to the TriCore Architecture. Where the TC1767 directly implements TriCore architectural functions, this manual simply refers to those functions as features of the TC1767. In all cases where this manual describes a TC1767 feature without referring to the TriCore Architecture, this means that the TC1767 is a direct implementation of the TriCore Architecture.

Where the TC1767 implements a subset of TriCore architectural features, this manual describes the TC1767 implementation, and then describes how it differs from the TriCore Architecture. Such differences between the TC1767 and the TriCore Architecture are documented in the section covering each such subject.

## 2.1.1 Related Documentations

A complete description of the TriCore architecture is found in the document entitled "TriCore Architecture Manual". The architecture of the TC1767 is described separately this way because of the configurable nature of the TriCore specification: Different versions of the architecture may contain a different mix of systems components. The TriCore architecture, however, remains constant across all derivative designs in order to preserve compatibility.

This Data Sheets together with the "TriCore Architecture Manual" are required to understand the complete TC1767 micro controller functionality.

## 2.1.2 Text Conventions

This document uses the following text conventions for named components of the TC1767:

- Functional units of the TC1767 are given in plain UPPER CASE. For example: "The SSC supports full-duplex and half-duplex synchronous communication".
- Pins using negative logic are indicated by an overline. For example: "The external reset pin, ESR0, has a dual function.".
- Bit fields and bits in registers are in general referenced as "Module\_Register name.Bit field" or "Module\_Register name.Bit". For example: "The Current CPU Priority Number bit field CPU\_ICR.CCPN is cleared". Most of the



## 2.2 System Architecture of the TC1767

The TC1767 combines three powerful technologies within one silicon die, achieving new levels of power, speed, and economy for embedded applications:

- Reduced Instruction Set Computing (RISC) processor architecture
- Digital Signal Processing (DSP) operations and addressing modes
- On-chip memories and peripherals

DSP operations and addressing modes provide the computational power necessary to efficiently analyze complex real-world signals. The RISC load/store architecture provides high computational bandwidth with low system cost. On-chip memory and peripherals are designed to support even the most demanding high-bandwidth real-time embedded control-systems tasks.

Additional high-level features of the TC1767 include:

- · Program Memory Unit instruction memory and instruction cache
- · Serial communication interfaces flexible synchronous and asynchronous modes
- · Peripheral Control Processor standalone data operations and interrupt servicing
- · DMA Controller DMA operations and interrupt servicing
- General-purpose timers
- High-performance on-chip buses
- On-chip debugging and emulation facilities
- Flexible interconnections to external components
- Flexible power-management

TC1767 clock frequencies:

- Maximum CPU clock frequency: 133 MHz<sup>1)</sup>
- Maximum PCP clock frequency: 133 MHz<sup>2)</sup>
- Maximum SPB frequency: 80 MHz<sup>3)</sup>

The TC1767 is a high-performance microcontroller with TriCore CPU, program and data memories, buses, bus arbitration, an interrupt controller, a peripheral control processor, a DMA controller and several on-chip peripherals. The TC1767 is designed to meet the needs of the most demanding embedded control systems applications where the competing issues of price/performance, real-time responsiveness, computational power, data bandwidth, and power consumption are key design elements.

The TC1767 offers several versatile on-chip peripheral units such as serial controllers, timer units, and Analog-to-Digital converters. Within the TC1767, all these peripheral units are connected to the TriCore CPU/system via the Flexible Peripheral Interconnect (FPI) Bus and the Local Memory Bus (LMB). Several I/O lines on the TC1767 ports are reserved for these peripheral units to communicate with the external world.

<sup>1)</sup> For CPU frequencies > 80 MHz, 2:1 mode has to be enabled. CPU 2:1 mode means:  $f_{SPB} = 0.5 * f_{CPU}$ 

<sup>2)</sup> For PCP frequencies > 80 MHz, 2:1 mode has to be enabled. PCP 2:1 mode means: f<sub>SPB</sub> = 0.5 \* f<sub>PCP</sub>

<sup>3)</sup> CPU 1:1 Mode means:  $f_{SPB} = f_{CPU}$ . PCP 1:1 mode means:  $f_{SPB} = f_{PCP}$ 



# 2.3.6 Program Memory Unit (PMU)

The devices of the AudoF family contain at least one Program Memory Unit. This is named "PMU0". Some devices contain additional PMUs which are named "PMU1", ...

In the TC1767, the PMU0 contains the following submodules:

- The Flash command and fetch control interface for Program Flash and Data Flash.
- The Overlay RAM interface with Online Data Acquisition (OLDA) support.
- The Boot ROM interface.
- The Emulation Memory interface.
- The Local Memory Bus LMB slave interface.

Following memories are controlled by and belong to the PMU0:

- 2 Mbyte of Program Flash memory (PFlash)
- 64 Kbyte of Data Flash memory (DFlash, represents 16 Kbyte EEPROM)
- 16 Kbyte of Boot ROM (BROM)
- 8 Kbyte Overlay RAM (OVRAM)

The following figure shows the block diagram of the PMU0:



Figure 3 PMU0 Basic Block Diagram



## 2.4.4 MultiCAN Controller

The MultiCAN module provides two independent CAN nodes in the PG-LQFP-176-5 package, representing two serial communication interfaces. The number of available message objects is 64.



Figure 8 Overview of the MultiCAN Module

The MultiCAN module contains two independently operating CAN nodes with Full-CAN functionality that are able to exchange Data and Remote Frames via a gateway function. Transmission and reception of CAN frames is handled in accordance to CAN specification V2.0 B (active). Each CAN node can receive and transmit standard frames with 11-bit identifiers as well as extended frames with 29-bit identifiers.

All two CAN nodes share a common set of message objects. Each message object can be individually allocated to one of the CAN nodes. Besides serving as a storage container for incoming and outgoing frames, message objects can be combined to build gateways between the CAN nodes or to set up a FIFO buffer.

The message objects are organized in double-chained linked lists, where each CAN node has its own list of message objects. A CAN node stores frames only into message objects that are allocated to the message object list of the CAN node, and it transmits only messages belonging to this message object list. A powerful, command-driven list controller performs all message object list operations.



- $f_{\rm GPTA}/4$  maximum input signal frequency in 2-sensor Mode,  $f_{\rm GPTA}/6$  maximum input signal frequency in 3-sensor Mode
- Duty Cycle Measurement (DCM)
  - Four independent units
  - 0 100% margin and time-out handling
  - $-f_{\rm GPTA}$  maximum resolution
  - $-f_{GPTA}/2$  maximum input signal frequency
  - Digital Phase Locked Loop (PLL)
  - One unit
  - Arbitrary multiplication factor between 1 and 65535
  - $f_{\text{GPTA}}$  maximum resolution
  - $-f_{GPTA}/2$  maximum input signal frequency
  - Clock Distribution Unit (CDU)
    - One unit
    - Provides nine clock output signals:

 $f_{\rm GPTA}$ , divided  $f_{\rm GPTA}$  clocks, FPC1/FPC4 outputs, DCM clock, LTC prescaler clock

## Signal Generation Unit

- Global Timers (GT)
  - Two independent units
  - Two operating modes (Free-Running Timer and Reload Timer)
  - 24-bit data width
  - $f_{\text{GPTA}}$  maximum resolution
  - $-f_{GPTA}/2$  maximum input signal frequency
- Global Timer Cell (GTC)
  - 32 units related to the Global Timers
  - Two operating modes (Capture, Compare and Capture after Compare)
  - 24-bit data width
  - $-f_{GPTA}$  maximum resolution
  - $-f_{GPTA}/2$  maximum input signal frequency
- Local Timer Cell (LTC)
  - 64 independent units
  - Three basic operating modes (Timer, Capture and Compare) for 63 units
  - Special compare modes for one unit
  - 16-bit data width
  - $-f_{\rm GPTA}$  maximum resolution
  - $f_{\text{GPTA}}/2$  maximum input signal frequency

### Interrupt Sharing Unit

· 143 interrupt sources, generating up to 46 service requests



# 2.4.7.2 FADC Short Description

## **General Features**

- Extreme fast conversion, 21 cycles of  $f_{FADC}$  clock (262.5 ns @  $f_{FADC}$  = 80 MHz)
- 10-bit A/D conversion (higher resolution can be achieved by averaging of consecutive conversions in digital data reduction filter)
- Successive approximation conversion method
- · Each differential input channel can also be used as single-ended input
- Offset calibration support for each channel
- Programmable gain of 1, 2, 4, or 8 for each channel
- Free-running (Channel Timers) or triggered conversion modes
- Trigger and gating control for external signals
- Built-in Channel Timers for internal triggering
- Channel timer request periods independently selectable for each channel
- Selectable, programmable digital anti-aliasing and data reduction filter block with four independent filter units



### Figure 13 Block Diagram of the FADC Module with 4 Input Channels

As shown in Figure 13, the main FADC functional blocks are:

• An Input Structure containing the differential inputs and impedance control.



# TC1767

#### Introduction



Figure 14 FADC Input Structure in TC1767

# 2.5 On-Chip Debug Support (OCDS)

The TC1767 contains resources for different kinds of "debugging", covering needs from software development to real-time-tuning. These resources are either embedded in specific modules (e.g. breakpoint logic of the TriCore) or part of a central peripheral (known as CERBERUS).

## 2.5.1 On-Chip Debug Support

The classic software debug approach (start/stop, single-stepping) is supported by several features labelled "OCDS Level 1":

- Run/stop and single-step execution independently for TriCore and PCP.
- Means to request all kinds of reset without usage of sideband pins.
- Halt-after-Reset for repeatable debug sessions.



## Pinning

Table	e 4 Pin 🛙	Definition	ns and	Functions (PG-LQFP-176-5 Package <sup>1)</sup> )
Pin	Symbol	Ctrl.	Туре	Function
Port	0	L		1
145	P0.0	I/O0	A1/	Port 0 General Purpose I/O Line 0
	IN0	I	PU	GPTA0 Input 0
	IN0	I		LTCA2 Input 0
	HWCFG0	I		Hardware Configuration Input 0
	OUT0	01		GPTA0 Output 0
	OUT56	O2		GPTA0 Output 56
	OUT0	O3		LTCA2 Output 0
146	P0.1	I/O0	A1/	Port 0 General Purpose I/O Line 1
	IN1	I	PU	GPTA0 Input 1
	IN1	I		LTCA2 Input 1
	HWCFG1	I		Hardware Configuration Input 1
	OUT1	01		GPTA0 Output 1
	OUT57	O2		GPTA0 Output 57
	OUT1	O3		LTCA2 Output 1
147	P0.2	I/O0	A1/	Port 0 General Purpose I/O Line 2
	IN2	I	PU	GPTA0 Input 2
	IN2	I		LTCA2 Input 2
	HWCFG2	I		Hardware Configuration Input 2
	OUT2	01		GPTA0 Output 2
	OUT58	O2		GPTA0 Output 58
	OUT2	O3		LTCA2 Output 2
148	P0.3	I/O0	A1/	Port 0 General Purpose I/O Line 3
	IN3	I	PU	GPTA0 Input 3
	IN3	I		LTCA2 Input 3
	HWCFG3	I	1	Hardware Configuration Input 3
	OUT3	01	1	GPTA0 Output 3
	OUT59	02	1	GPTA0 Output 59
	OUT3	O3	-	LTCA2 Output 3



## Pinning

Table	e 4 Pin D	efinitio	ns and	Functions (PG-LQFP-176-5 Package <sup>1)</sup> ) (cont'd)
Pin	Symbol	Ctrl.	Туре	Function
97	P1.11	I/O0	A2/	Port 1 General Purpose I/O Line 11
	IN27	I	PU	GPTA0 Input 27
	IN51	I		GPTA0 Input 51
	SCLK1B	I		SSC1 Clock Input B
	OUT27	01		GPTA0 Output 27
	OUT51	O2		GPTA0 Output 51
	SCLK1B	O3		SSC1 Clock Output B
73	P1.12	I/O0	A1/	Port 1 General Purpose I/O Line 12
	IN16	I	PU	LTCA2 Input 16
	AD0EMUX0	01		ADC0 External Multiplexer Control Output 0
	AD0EMUX0	02		ADC0 External Multiplexer Control Output 0
	OUT16	O3		LTCA2 Output 16
72	P1.13	I/O0	A1/	Port 1 General Purpose I/O Line 13
	IN17	I	PU	LTCA2 Input 17
	AD0EMUX1	01		ADC0 External Multiplexer Control Output 1
	AD0EMUX1	02		ADC0 External Multiplexer Control Output 1
	OUT17	O3		LTCA2 Output 17
71	P1.14	I/O0	A1/	Port 1 General Purpose I/O Line 14
	IN18	I	PU	LTCA2 Input 18
	AD0EMUX2	01		ADC0 External Multiplexer Control Output 2
	AD0EMUX2	O2		ADC0 External Multiplexer Control Output 2
	OUT18	O3		LTCA2 Output 18
117	P1.15	I/O0	A2/	Port 1 General Purpose I/O Line 15
	BRKIN	I	PU	Break Input
	Reserved	01		-
	Reserved	O2	1	-
	Reserved	O3	1	-
	BRKOUT	0		Break Output (controlled by OCDS module)
Port	2	4		



## TC1767

## Pinning

Tabl	able 4 Pin Definitions and Functions (PG-LQFP-176-5 Package <sup>1</sup> ) (cont'd)							
Pin	Symbol	Ctrl.	Туре	Function				
74	P2.0	I/O0	A2/	Port 2 General Purpose I/O Line 0				
	IN32	I	PU	GPTA0 Input 32				
	OUT32	01		GPTA0 Output 32				
	TCLK0	02		MLI0 Transmitter Clock Output 0				
	OUT28	O3		LTCA2 Output 28				
75	P2.1	I/O0	A2/	Port 2 General Purpose I/O Line 1				
	IN33	I	PU	GPTA0 Input 33				
	TREADY0A	I		MLI0 Transmitter Ready Input A				
	OUT33	01		GPTA0 Output 33				
	SLSO03	02		SSC0 Slave Select Output Line 3				
	SLSO13	O3		SSC1 Slave Select Output Line 3				
76	P2.2	I/O0	A2/	Port 2 General Purpose I/O Line 2				
	IN34	I	PU	GPTA0 Input 34				
	OUT34	01		GPTA0 Output 34				
	TVALID0	02		MLI0 Transmitter Valid Output				
	OUT29	O3		LTCA2 Output 29				
77	P2.3	I/O0	A2/	Port 2 General Purpose I/O Line 3				
	IN35	I	PU	GPTA0 Input 35				
	OUT35	01		GPTA0 Output 35				
	TDATA0	02		MLI0 Transmitter Data Output				
	OUT30	O3		LTCA2 Output 30				
78	P2.4	I/O0	A2/	Port 2 General Purpose I/O Line 4				
	IN36	I	PU	GPTA0 Input 36				
	RCLK0A	I		MLI Receiver Clock Input A				
	OUT36	01	1	GPTA0 Output 36				
	OUT36	O2		GPTA0 Output 36				
	OUT31	O3		LTCA2 Output 31				



## 5.1.4 Operating Conditions

The following operating conditions must not be exceeded in order to ensure correct operation of the TC1767. All parameters specified in the following table refer to these operating conditions, unless otherwise noted.

Parameter	Symbol			Values	5	Unit	Note /	
			Min.	Тур.	Max.		Test Condition	
Digital supply voltage <sup>1)</sup>	$V_{\rm DD}$ $V_{\rm DDOSO}$	SR SR	1.42	-	1.58 <sup>2)</sup>	V	-	
	$V_{ m DDP}$ $V_{ m DDOSO}$	SR <sub>C3</sub> SR	3.13	-	3.47 <sup>3)</sup>	V	For Class A pins $(3.3 V \pm 5\%)$	
	$V_{\sf DDFL3}$	SR	3.13	_	3.47 <sup>3)</sup>	V	_	
Analog supply voltages	$V_{DDMF}$	SR	3.13	-	3.47 <sup>3)</sup>	V	FADC	
	$V_{DDAF}$	SR	1.42	-	1.58 <sup>2)</sup>	V	FADC	
	V <sub>DDM</sub>	SR	4.75	-	5.25	V	For Class D <sub>E</sub> pins, ADC	
Digital ground voltage	V <sub>SS</sub>	SR	0	-	-	V	-	
Ambient temperature under bias	T <sub>A</sub>	SR	-	-40	125	°C	_	
Analog supply voltages	_		_	_	_	_	See separate specification Page 88, Page 93	
Overload current at class D pins	I <sub>OV</sub>		-1	-	3	mA	4)	
Sum of overload current at class D pins	$\Sigma  I_{OV} $		-	_	10	mA	per single ADC	
Overload coupling	$K_{OVAP}$		-	_	5×10 <sup>-5</sup>		0 < I <sub>OV</sub> < 3 mA	
factor for analog inputs <sup>5)</sup>	$K_{\rm OVAN}$		-	-	5×10 <sup>-4</sup>		-1 mA < I <sub>OV</sub> < 0	
CPU & LMB Bus Frequency	$f_{CPU}$	SR	-	-	133 80	MHz	Derivative dependent	
PCP Frequency	$f_{PCP}$	SR	-	-	133 80	MHz	<sup>6)</sup> Derivative dependent	
FPI Bus Frequency	$f_{\rm SYS}$	SR	-	-	80	MHz	6)	
Short circuit current	I <sub>SC</sub>	SR	-5	-	+5	mA	7)	

### Table 9 Operating Condition Parameters



## 5.2 DC Parameters

# 5.2.1 Input/Output Pins

### Table 11 Input/Output DC-Characteristics (Operating Conditions apply)

Parameter	Symbo	I	Value	s	Unit	Note / Test Condition	
		Min.	Тур.	Max.	_		
General Paramete	rs		1			l	
Pull-up current <sup>1)</sup>	I <sub>PUH</sub>   C	10 C	-	100	μA	V <sub>IN</sub> < V <sub>IHAmin</sub> ; class A1/A2/F/Input pads.	
Pull-down current <sup>1)</sup>	I <sub>PDL</sub>   C	10 C	-	150	μA	V <sub>IN</sub> >V <sub>ILAmax</sub> ; class A1/A2/F/Input pads.	
Pin capacitance <sup>1)</sup> (Digital I/O)	C <sub>IO</sub>	c –	-	10	pF	f = 1 MHz $T_A$ = 25 °C	
Input only Pads (	/ <sub>DDP</sub> = 3.	13 to 3.47	V = 3	.3 V ± 5%	b)		
Input low voltage	V <sub>ILI</sub> SI	-0.3 २	-	$0.36 \times V_{ m DDP}$	V	-	
Input high voltage	V <sub>IHI</sub> SI	0.62 × V <sub>DDP</sub>	-	V <sub>DDP</sub> + 0.3 or max. 3.6	V	Whatever is lower	
Ratio $V_{\rm IL}/V_{\rm IH}$	C	C 0.58	-	-	-	-	
Input high voltage TRST, TCK	V <sub>IHJ</sub> SI	R 0.64 × V <sub>DDP</sub>	-	V <sub>DDP</sub> + 0.3 or max. 3.6	V	Whatever is lower	
Input hysteresis	HYSI C	0.1 × C V <sub>DDP</sub>	-	-	V	4)	
Input leakage current <sup>2)</sup>	I <sub>OZI</sub> C	c –	-	±3000 ±6000	nA	$((V_{DDP}/2)-1) < V_{IN} < ((V_{DDP}/2)+1)$ Otherwise	
Spike filter always blocked pulse duration	t <sub>SF1</sub> C	c –	-	10	ns		



# 5.2.2 Analog to Digital Converters (ADC0/ADC1)

All ADC parameters are optimized for and valid in the range of  $V_{\rm DDM}$  = 5V  $\pm$  5%.

Parameter	Symbo	bl	V	alues		Unit	Note /
			Min.	Тур.	Max.		Test Condition
Analog supply	$V_{\rm DDM}$	SR	4.75	5	5.25	V	-
voltage			3.13	3.3	3.47 <sup>1)</sup>	V	-
	$V_{DD}$	SR	1.42	1.5	1.58 <sup>2)</sup>	V	Power supply for ADC digital part, internal supply
Analog ground voltage	$V_{\rm SSM}$	SR	-0.1	_	0.1	V	-
Analog reference voltage <sup>14)</sup>	V <sub>AREFx</sub>	SR	V <sub>AGNDx</sub> +1 V	V <sub>DDM</sub>	V <sub>DDM</sub> + 0.05 1)3)4)	V	-
Analog reference ground <sup>14)</sup>	V <sub>AGNDx</sub>	SR	V <sub>SSMx</sub> - 0.05V	0	V <sub>AREF</sub> - 1V	V	-
Analog input voltage range	$V_{AIN}$	SR	$V_{AGNDx}$	_	$V_{AREFx}$	V	-
Analog reference voltage range <sup>5)14)</sup>	$V_{\text{AREFx}}$ - $V_{\text{AGNDx}}$	SR	V <sub>DDM</sub> /2	-	V <sub>DDM</sub> + 0.05	V	_
Converter Clock	f <sub>ADC</sub> S	SR	1	-	80	MHz	-
Internal ADC clocks	$f_{\sf ADCI}$	СС	0.5	_	10	MHz	-
Sample time	t <sub>S</sub>	СС	2	-	257	$T_{\rm ADCI}$	-
Total unadjusted error <sup>5)</sup>	TUE <sup>6)</sup>	СС	_	_	±4	LSB	12-bit conversion, without noise <sup>7)8)</sup>
			_	-	±2	LSB	10-bit conversion <sup>8)</sup>
			-	-	±1	LSB	8-bit conversion <sup>8)</sup>
DNL error <sup>9) 5)</sup>	$EA_{DNL}$	сс	_	±1.5	±3.0	LSB	12-bit conversion without noise <sup>8)10)</sup>
INL error <sup>9)5)</sup>	EA <sub>INL</sub>	СС	-	±1.5	±3.0	LSB	12-bit conversion without noise <sup>8)10)</sup>
Gain error <sup>9)5)</sup>	$EA_{GAIN}$	СС	-	±0.5	±3.5	LSB	12-bit conversion without noise <sup>8)10)</sup>

 Table 12
 ADC Characteristics (Operating Conditions apply)



## 5.2.6 Power Supply Current

The default test conditions (differences explicitly specified) are:  $V_{\text{DD}}$  = 1.58 V,  $V_{\text{DDP}}$  = 3.47 V,  $T_{\text{j}}$ =150°C. All other operating conditions apply.

Table 17	Power Supply	Currente	Maximum	Power	Consumption
	Fower Suppry	currents,	Maximum	rower	Consumption

Parameter	Symbol			Value	S	Unit	Note /	
			Min.	Тур.	Max.		Test Condition	
Core active mode supply current <sup>1) 2)</sup>	I <sub>DD</sub>	CC	-	-	330	mA	<i>f</i> <sub>CPU</sub> =133 MHz <i>f</i> <sub>CPU</sub> / <i>f</i> <sub>SYS</sub> = 2:1	
Realistic core active mode supply current <sup>3)4)</sup>			-	-	230	mA	V <sub>DD</sub> = 1.53 V, T <sub>J</sub> = 150°C	
FADC 3.3 V analog supply current	$I_{DDMF}$	СС	-	-	10	mA	_	
FADC 1.5 V analog supply current	$I_{DDAF}$	СС	-	-	10	mA	_ <sup>4)</sup>	
Flash memory 3.3 V supply current	I <sub>DDFL3R</sub>	CC	-	-	60	mA	continuously reading the Flash memory <sup>5)</sup>	
	$I_{\rm DDFL3E}$	СС	-	-	61	mA	Flash memory erase-verify <sup>6)</sup>	
Oscillator 1.5 V supply	IDDOSC	CC	-	-	3	mA	- <sup>4)</sup>	
Oscillator 3.3 V supply	$I_{\rm DDOSC3}$	CC	-	-	10	mA	- <sup>4)</sup>	
LVDS 3.3 V supply	$I_{\rm LVDS}$		-	-	15	mA	in total for two pairs	
Pad currents,sum of	$I_{DDP}$	CC	-	-	16	mA	- <sup>4) 7)</sup>	
$V_{\rm DDP}$ 3.3 V supplies	I <sub>DDP_FP</sub>	CC	-	-	34	mA	<i>I</i> <sub>DDP</sub> including Data Flash programming current <sup>4) 8)</sup>	
ADC 5 V power supply	$I_{\rm DDM}$	CC	_	2	3	mA	ADC0 / 1	
Maximum Average Power Dissipation <sup>1)</sup>	P <sub>D</sub>	SR	_	820	990	mW	worst case $T_{\rm A}$ = 125°C, $P_{\rm D} \times R_{\Theta \rm JA}$ < 25°C	

1) Infineon Power Loop: CPU and PCP running, all peripherals active. The power consumption of each custom application will most probably be lower than this value, but must be evaluated separately..

<sup>2)</sup> The  $I_{\text{DD}}$  maximum value is 275 mA at  $f_{\text{CPU}}$  = 80 MHz, constant  $T_{\text{J}}$  = 150°C, for the Infineon Max Power Loop. The dependency in this range is, at constant junction temperature, linear.  $f_{\text{CPU}}/f_{\text{SYS}}$  = 1:1 mode.



## 5.3.2 Output Rise/Fall Times

### Table 18 Output Rise/Fall Times (Operating Conditions apply)

Parameter	Symbol		Value	es	Unit	Note / Test Condition	
		Min.	Тур.	Max.	1		
Class A1 Pads							
Rise/fall times <sup>1)</sup>	<i>t</i> <sub>RA1</sub> , <i>t</i> <sub>FA1</sub>	_	_	50 140 18000 150 550 65000	ns	Regular (medium) driver, 50 pF Regular (medium) driver, 150 pF Regular (medium) driver, 20 nF Weak driver, 20 pF Weak driver, 150 pF Weak driver, 20 000 pF	
Class A2 Pads							
Rise/fall times	t <sub>RA2</sub> , t <sub>FA2</sub>	_	-	3.7 7.5 7 18 50 140 18000 150 550 65000	ns	Strong driver, sharp edge, 50 pF Strong driver, sharp edge, 100pF Strong driver, med. edge, 50 pF Strong driver, soft edge, 50 pF Medium driver, 50 pF Medium driver, 150 pF Medium driver, 20 000 pF Weak driver, 20 pF Weak driver, 150 pF Weak driver, 20 000 pF	
Class F Pads							
Rise/fall times	$t_{RF1}, t_{FF1}$	-	-	2	ns	LVDS Mode	
Rise/fall times	$t_{RF2}, t_{FF2}$	-	-	60	ns	CMOS Mode, 50 pF	

1) Not all parameters are subject to production test, but verified by design/characterization and test correlation.



## 5.3.3 Power Sequencing



Figure 24 5 V / 3.3 V / 1.5 V Power-Up/Down Sequence

The following list of rules applies to the power-up/down sequence:

- All ground pins V<sub>SS</sub> must be externally connected to one single star point in the system. Regarding the DC current component, all ground pins are internally directly connected.
- 1. At any moment,

each power supply must be higher than any lower\_power\_supply - 0.5 V, or:  $V_{DD5} > V_{DD3,3} - 0.5 V$ ;  $V_{DD5} > V_{DD1,5} - 0.5 V$ ;  $V_{DD3,3} > V_{DD1,5} - 0.5 V$ , see Figure 24.

2. During power-up and power-down, the voltage difference between the power supply pins of the same voltage (3.3 V, 1.5 V, and 5 V) with different names (for example  $V_{\text{DDP}}$ ,  $V_{\text{DDFL3}}$ ...), that are internaly connected via diodes must be lower than 100 mV. On the other hand, all power supply pins with the same name (for example all  $V_{\text{DDP}}$ ), are internaly directly connected. It is recommended that the power pins of the same voltage are driven by a single power supply.



With rising number *m* of clock cycles the maximum jitter increases linearly up to a value of *m* that is defined by the K2-factor of the PLL. Beyond this value of *m* the maximum accumulated jitter remains at a constant value. Further, a lower LMB-Bus clock frequency  $f_{\rm IMB}$  results in a higher absolute maximum jitter value.

**Figure 26** gives the jitter curves for several K2 /  $f_{LMB}$  combinations.



#### Figure 26 Approximated Maximum Accumulated PLL Jitter for Typical LMB-Bus Clock Frequencies $f_{IMB}$

- Note: The specified PLL jitter values are valid if the capacitive load per output pin does not exceed  $C_L = 20 \text{ pF}$  with the maximum driver and sharp edge. In case of applications with many pins with high loads, driver strengths and toggle rates the specified jitter values could be exceeded.
- Note: The maximum peak-to-peak noise on the pad supply voltage, measured between  $V_{\text{DDOSC3}}$  at pin 106 and  $V_{\text{SSOSC}}$  at pin 104, is limited to a peak-to-peak voltage of  $V_{\text{PP}}$  = 100 mV for noise frequencies below 300 KHz and  $V_{\text{PP}}$  = 40 mV for noise frequencies above 300 KHz.

The maximum peak-to peak noise on the pad supply votage, measured between  $V_{\text{DDOSC}}$  at pin 105 and  $V_{\text{SSOSC}}$  at pin 104, is limited to a peak-to-peak voltage of  $V_{\text{PP}}$  = 100 mV for noise frequencies below 300 KHz and  $V_{\text{PP}}$  = 40 mV for noise frequencies above 300 KHz.



# Table 23 MLI Transmitter/Receiver Timing

(Operating Conditions apply), C<sub>L</sub> = 50 pF

Parameter	Symbol			Values	Unit	Note /	
			Min.	Тур.	Max.		Test Co ndition
MLI Transmitter Timing							
TCLK clock period	t <sub>10</sub>	CC	$2 \times T_{\mathrm{MLI}}$	-	-	ns	1)
TCLK high time	<i>t</i> <sub>11</sub>	CC	$0.45 \times t_{10}$	$0.5 \times t_{10}$	$0.55 \times t_{10}$	ns	2)3)
TCLK low time	t <sub>12</sub>	CC	$0.45 \times t_{10}$	$0.5 \times t_{10}$	$0.55 \times t_{10}$	ns	2)3)
TCLK rise time	t <sub>13</sub>	СС	-	-	4)	ns	-
TCLK fall time	t <sub>14</sub>	CC	-	-	4)	ns	-
TDATA/TVALID output delay time	t <sub>15</sub>	CC	-3	-	4.4	ns	-
TREADY setup time to TCLK rising edge	t <sub>16</sub>	SR	18	-	-	ns	-
TREADY hold time from TCLK rising edge	t <sub>17</sub>	SR	0	-	-	ns	-
MLI Receiver Timing							
RCLK clock period	<i>t</i> <sub>20</sub>	SR	$1 \times T_{\rm MLI}$	-	-	ns	1)
RCLK high time	<i>t</i> <sub>21</sub>	SR	-	$0.5 \times t_{20}$	-	ns	5)6)
RCLK low time	t <sub>22</sub>	SR	-	$0.5 \times t_{20}$	-	ns	5)6)
RCLK rise time	t <sub>23</sub>	SR	-	-	4	ns	7)
RCLK fall time	t <sub>24</sub>	SR	-	-	4	ns	7)
RDATA/RVALID setup time to RCLK falling edge	t <sub>25</sub>	SR	4.2	-	-	ns	-
RDATA/RVALID hold time from RCLK rising edge	t <sub>26</sub>	SR	2.2	-	-	ns	-
RREADY output delay time	t <sub>27</sub>	CC	0	-	16	ns	-

1)  $T_{\text{MLImin.}} = T_{\text{SYS}} = 1/f_{\text{SYS}}$ . When  $f_{\text{SYS}} = 80$  MHz,  $t_{10} = 25$  ns and  $t_{20} = 12.5$  ns.

2) The following formula is valid:  $t_{11} + t_{12} = t_{10}$ 

3) The min./max. TCLK low/high times  $t_{11}/t_{12}$  include the PLL jitter of  $f_{SYS}$ . Fractional divider settings must be regarded additionally to  $t_{11}/t_{12}$ .

4) For high-speed MLI interface, strong driver sharp edge selection (class A2 pad) is recommended for TCLK.

5) The following formula is valid:  $t_{21} + t_{22} = t_{20}$ 

6) The min. and max. value of is parameter can be adjusted by considering the other receiver timing parameters.



## 5.4 Package and Reliability

## 5.4.1 Package Parameters

### Table 26 Thermal Parameters (Operating Conditions apply)

Device	Package	R <sub>⊕JCT</sub> <sup>1)</sup>	R <sub>☉JCB</sub> <sup>1)</sup>	$R_{\odot JLeads}^{(1)}$	Unit	Note
TC1767	PG-LQFP-176-5	6.5	5.5	23	K/W	

 The top and bottom thermal resistances between the case and the ambient (R<sub>TCAT</sub>, R<sub>TCAB</sub>) are to be combined with the thermal resistances between the junction and the case given above (R<sub>TJCT</sub>, R<sub>TJCB</sub>), in order to calculate the total thermal resistance between the junction and the ambient (R<sub>TJA</sub>). The thermal resistances between the case and the ambient (R<sub>TCAT</sub>, R<sub>TCAB</sub>) depend on the external system (PCB, case) characteristics, and are under user responsibility.

The junction temperature can be calculated using the following equation:  $T_J = T_A + R_{TJA} \times P_D$ , where the  $R_{TJA}$  is the total thermal resistance between the junction and the ambient. This total junction ambient resistance  $R_{TJA}$  can be obtained from the upper four partial thermal resistances.

Thermal resistances as measured by the 'cold plate method' (MIL SPEC-883 Method 1012.1).



## 5.4.4 Quality Declarations

#### Table 28 Quality Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Тур.	Max.		
Operation Lifetime <sup>1)</sup>	t <sub>OP</sub>	-	-	24000	hours	_2) 3)
ESD susceptibility according to Human Body Model (HBM)	V <sub>HBM</sub>	-	-	2000	V	Conforming to JESD22-A114-B
ESD susceptibility of the LVDS pins	V <sub>HBM1</sub>	-	-	500	V	-
ESD susceptibility according to Charged Device Model (CDM)	V <sub>CDM</sub>	-	-	500	V	Conforming to JESD22-C101-C
Moisture Sensitivity Level	MSL	-	-	3	-	Conforming to Jedec J-STD-020C for 240°C

1) This lifetime refers only to the time when the device is powered on.

 For worst-case temperature profile equivalent to: 2000 hours at T<sub>i</sub> = 150°C 16000 hours at T<sub>i</sub> = 125°C

6000 hours at T<sub>j</sub> = 110°C

3) This 30000 hours worst-case temperature profile is also covered: 300 hours at  $T_i = 150^{\circ}$ C 1000 hours at  $T_i = 140^{\circ}$ C 1700 hours at  $T_i = 130^{\circ}$ C 24000 hours at  $T_i = 120^{\circ}$ C 3000 hours at  $T_i = 110^{\circ}$ C